

P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)			
- 30	0.030 at V _{GS} = - 10 V	- 5.1	5.1 nC			
	0.042 at V _{GS} = - 4.5 V	- 4.1	5.1 nC			

FEATURES

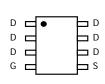
- Halogen-free According to IEC 61249-2-21 Available
- Trench Power MOSFET

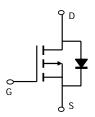
COMPLIANT HALOGEN FREE

APPLICATIONS

· Load Switch







Parameter		Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	- 30	V	
Gate-Source Voltage		V_{GS}	± 20	v
	T _C = 25 °C		- 5.1	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	1 . 1	- 4.1	
Continuous Diam Current (1) = 130 °C)	T _A = 25 °C	I _D	- 4.1 ^{b, c}	
	T _A = 70 °C	1	- 3.3 ^{b, c}	A
Pulsed Drain Current		I _{DM}	- 20	
	T _C = 25 °C		- 2.5	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	- 1.67 ^{b, c}	
	T _C = 25 °C		3.0	
Maximum Dawar Dissination	T _C = 70 °C	D.	2.0	W
Maximum Power Dissipation	T _A = 25 °C	- P _D	2.0 ^{b, c}	VV
	T _A = 70 °C	1	1.3 ^{b, c}	
Operating Junction and Storage Temperature	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R_{thJA}	55	62.5	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	34	41	5/ ۷۷	

- a. Based on T_C = 25 °C.
 b. Surface Mounted on 1" x 1" FR4 board.
- d. Maximum under Steady State conditions is 110 °C/W.

服务热线:400-655-8788



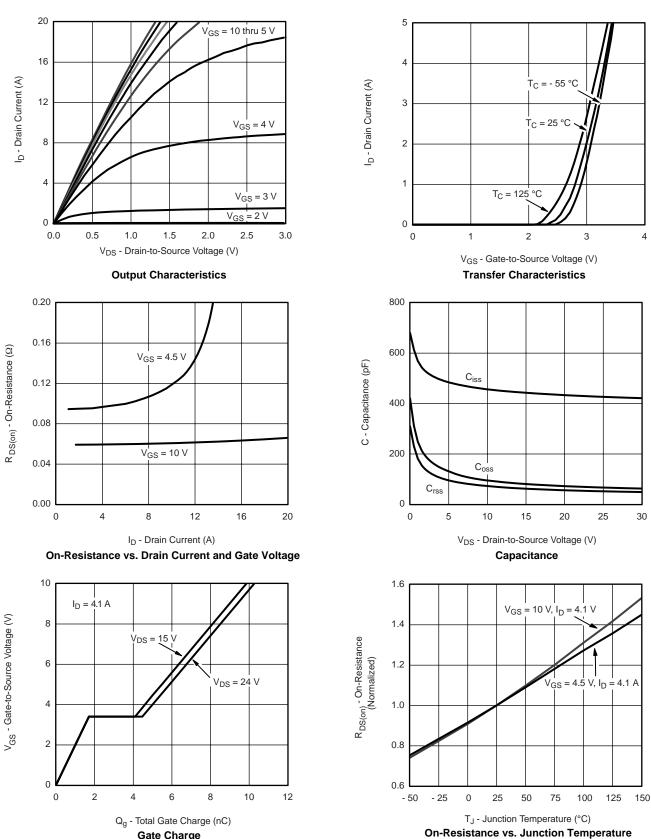
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					l		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250A		- 31		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		4.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.0		- 3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oata Vallana Brain Oamant		$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$			- 1	μΑ	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			- 10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 20			Α	
		V _{GS} = - 10 V, I _D = - 4.1 A	0.030			 	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 1.0 A		0.042		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 4.1 A		8		S	
Dynamic ^b				<u> </u>			
Input Capacitance	C _{iss}			450		pF	
Output Capacitance	C _{oss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		80			
Reverse Transfer Capacitance	C _{rss}			63			
Total Cata Charra		V _{DS} = - 15 V, V _{GS} = - 10 V, I _D = - 4.1 A		10	15	nC	
Total Gate Charge	Q_g			5.1	8		
Gate-Source Charge	Q_{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -4.1 \text{ A}$		1.8			
Gate-Drain Charge	Q_{gd}			2.5			
Gate Resistance	R_{g}	f = 1 MHz		7		Ω	
Turn-On Delay Time	t _{d(on)}			40	60	ns	
Rise Time	t _r	V_{DD} = - 15 V, R_L = 4.6 Ω		80	120		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ - 3.3 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		20	30		
Fall Time	t _f			12	20		
Turn-On Delay Time	t _{d(on)}			5	10		
Rise Time	t _r	V_{DD} = - 15 V, R_L = 4.6 Ω		13	20		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ - 3.3 A, V_{GEN} = - 10 V, R_g = 1 Ω		20	30		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 2.5	^	
Pulse Diode Forward Current ^a	I _{SM}				- 20] A	
Body Diode Voltage	V _{SD}	I _S = - 3.3 A		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			20	30	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 00 A 45/44 400 A / T 05 00		20	30	nC	
Reverse Recovery Fall Time	t _a	$I_F = -3.3 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		14			
Reverse Recovery Rise Time	t _b			6		ns	

- a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 % b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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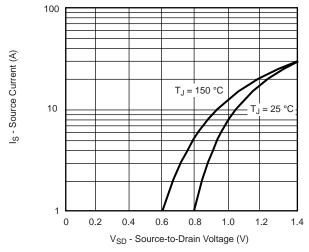


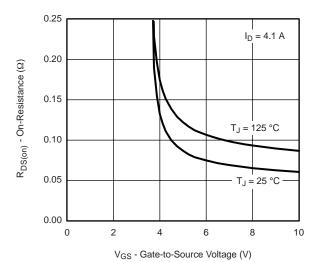


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Gate Charge

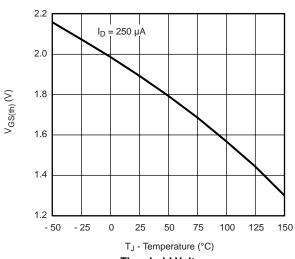


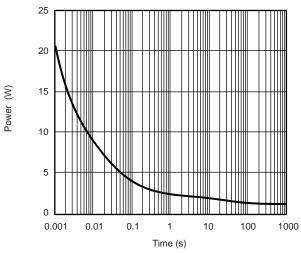




Source-Drain Diode Forward Voltage

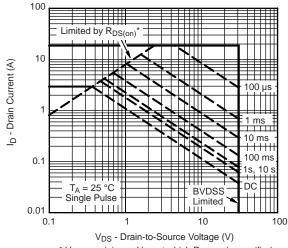






Threshold Voltage

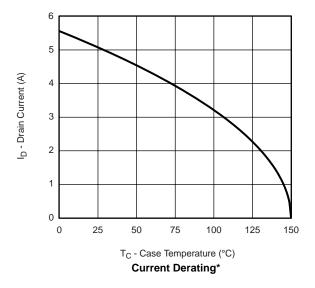
Single Pulse Power

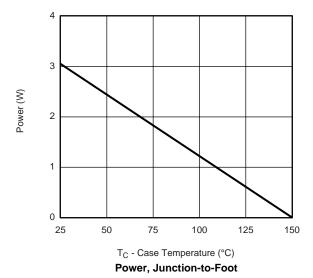


* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area



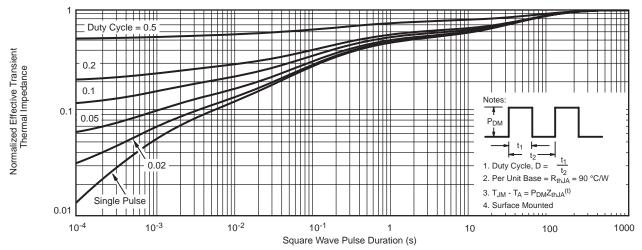




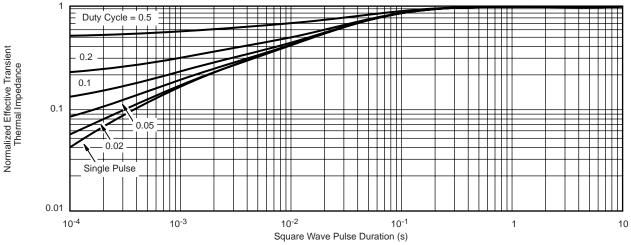
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^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

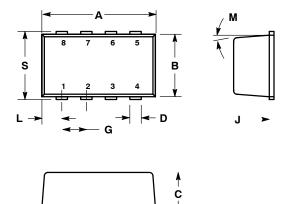


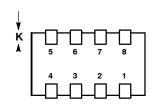
Normalized Thermal Transient Impedance, Junction-to-Foot



PACKAGE DIMENSIONS

ChipFET CASE 1206A-03 ISSUE D





STYLE 2:

- 2. GATE 1
- 4. GATE 2

- 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 8. DRAIN 1

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
 MOLD GATE BURRS SHALL NOT EXCEED 0.13 MM PER SIDE.
 LEADFRAME TO MOLDED BODY OFFSET IN HORIZONTAL AND VERTICAL SHALL NOT EXCEED 0.08 MM.
 DIMENSIONS A AND B EXCLUSIVE OF MOLD GATE BURRS.
 NO MOLD FLASH ALLOWED ON THE TOP AND BOTTOM LEAD SURFACE.
 1206A-01 AND 1206A-02 OBSOLETE. NEW STANDARD IS 1206A-03.

	MILLIN	METERS	INC	ICHES		
DIM	MIN	MAX	MIN	MAX		
Α	2.95	3.10	0.116	0.122		
В	1.55	1.70	0.061	0.067		
C	1.00	1.10	0.039	0.043		
D	0.25	0.35	0.010	0.014		
G	0.65 BSC		0.02	BSC		
J	0.10	0.20	0.004	0.008		
K	0.28	0.42	0.011	0.017		
L	0.55 BSC		0.02	2 BSC		
M	5° NOM		5 ° NOM			
S	1.80	2.00	0.072	0.080		



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